



Modeling a Circular Membrane Under Pressure

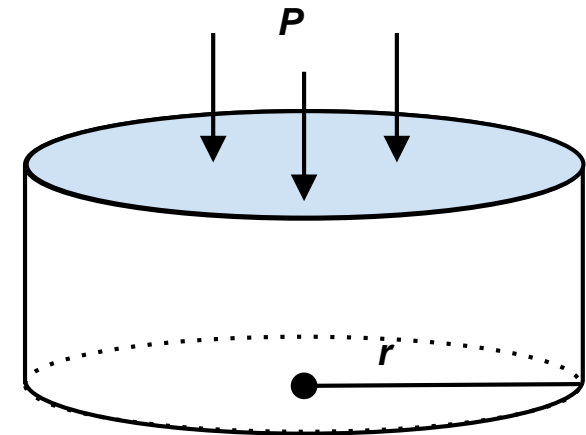
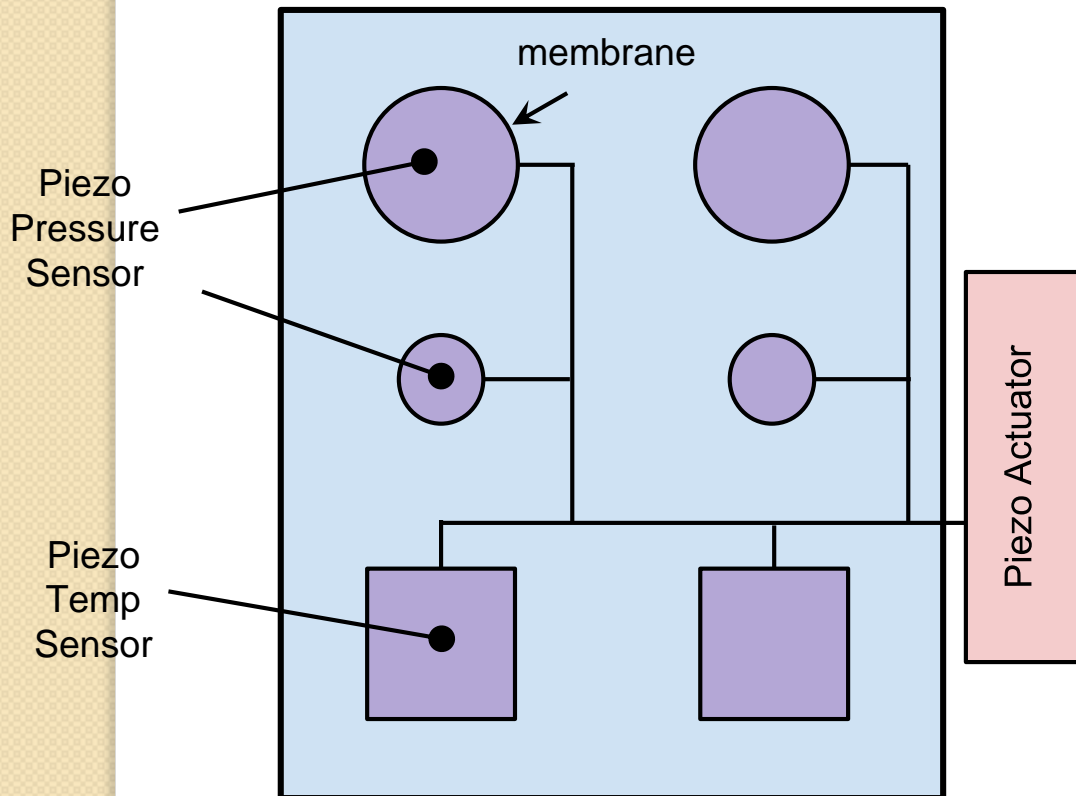
Kirti Mansukhani and Rachel Nancollas

EE C291 – Spring 2013

FINAL PROJECT PRESENTATION

Application: MEMS Pressure Sensor

- Pressure increases membrane resonant freq.
- Size membranes under pressure to have same frequency range as other sensors
- **Goal:** do this analytically



$$\omega = f(P, r)$$

Project Approach

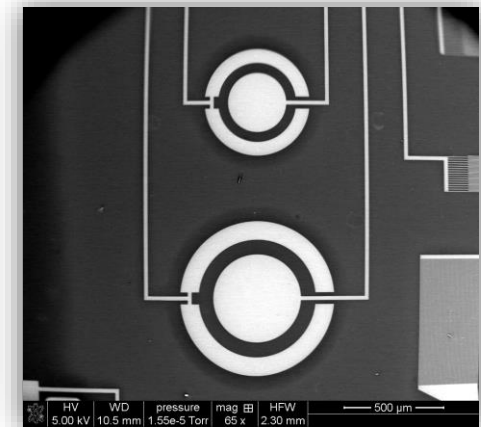
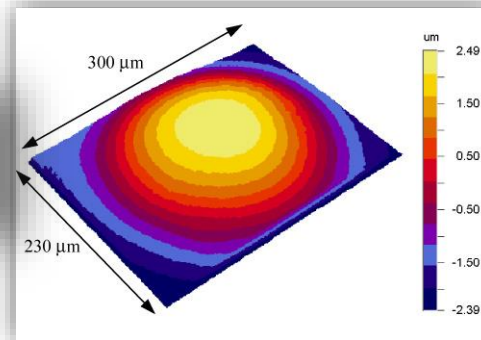
- Find resonant frequency of a membrane as a function of applied pressure
- Compare three methods:
 - Analytical (Hankel Transformation and SOV)
 - Numerical (Finite Element Analysis - FEA)
 - Experimental (using MEMS pressure sensor)

$$\nabla^2 u(r, t) = \frac{1}{cm^2} u_{tt}(r, t) - \frac{P(r)}{T_m}$$

$$u(r = a, t) = 0 \text{ (BC)}$$

$$u(r, t = 0) = 0 \text{ (IC)}$$

$$u_t(r, t = 0) = 0 \text{ (IC)}$$



Actual MEMS Pressure Sensor on a chip

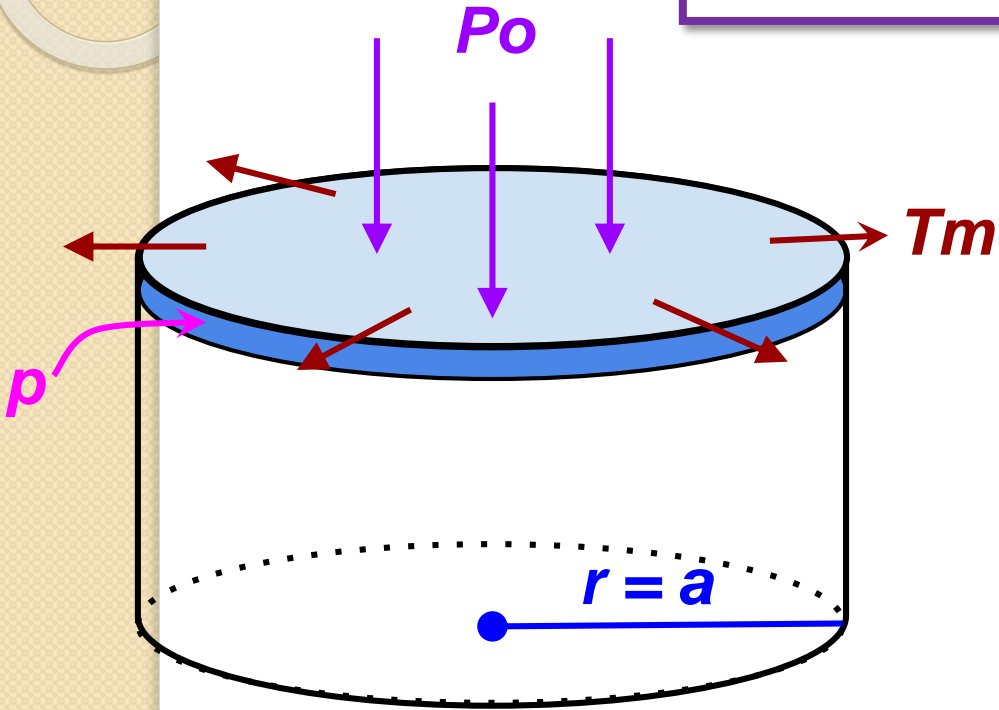
Membrane Model

$$\nabla^2 u(r, t) = \frac{1}{cm^2} u_{tt}(r, t) - \frac{P(r)}{T_m}$$

$$u(r = a, t) = 0 \text{ (BC)}$$

$$u(r, t = 0) = 0 \text{ (IC)}$$

$$u_t(r, t = 0) = 0 \text{ (IC)}$$



- P_o = pressure
- T_m = membrane
- ρ = density
- r = radius
- $u(r, t)$ = deflection
- $cm^2 = \frac{T_m}{\rho}$

Membrane tension is calculated as a function of the pressure: $T_m = f(P_o)$

Analytical: Using Hankel Transforms

$$\nabla^2 u(r, t) = \frac{1}{cm^2} u_{tt}(r, t) - \frac{P(r)}{T_m}$$

Take **Hankel** Transform
 $\mathbf{H}\{u(r, t)\} = \underline{U}(X, t)$

Take **Laplace** Transform
 $\mathbf{L}\{\underline{U}(X, t)\} = \underline{\underline{U}}(X, s)$

Rearrange terms and use properties of **convolution**

This allows you to take \mathbf{L}^{-1}
 $\mathbf{L}^{-1}\{\underline{\underline{U}}(X, s)\} = \underline{U}(X, t)$

Rearrange terms to take \mathbf{H}^{-1}
 $\mathbf{H}^{-1}\{\underline{U}(X, t)\} = u(r, t)$

Apply **IC and BC** and simplify

What's a Hankel Transform?
 Laplace Transform : Hankel Transform
 :: Sinusoids : Bessel Functions

$$u(r, t) = \frac{P_o}{T_m} \left[\frac{(a^2 - r^2)}{4} - 2a^2 \sum_{i=1,2}^{\infty} \frac{J_o\left(\frac{\lambda_i r}{a}\right)}{\lambda_i^3 J_1(\lambda_i)} \cos\left(\frac{\lambda_i cmt}{a}\right) \right]$$

Analytical - Using SOV:

$$\nabla^2 u(r, t) = \frac{1}{cm^2} u_{tt}(r, t) - \frac{P(r)}{T_m}$$

Assume: $u(r, t) = \psi(r) + \phi(r, t)$

Particular

$$\frac{1}{r} \psi_r + \psi_{rr} = \frac{P_o}{T_m}$$

ODE - Solve!

$$\psi(r) = -\frac{P_o}{4T_m} (a^2 - r^2)$$

Homogeneous

$$\frac{1}{r} \phi_r + \phi_{rr} = \frac{1}{cm^2} \phi_{tt}$$

Solve with SOV

$$\phi(r, t) = A J_0 \left(\frac{\lambda_i}{a} r \right) \cos \left(\frac{cm \lambda_i}{a} t \right)$$



$$u(r, t) = \frac{P_o}{T_m} \left[\frac{(a^2 - r^2)}{4} - 2a^2 \sum_{i=1,2}^{\infty} \frac{J_0 \left(\frac{\lambda_i}{a} r \right)}{\lambda_i^3 J_1(\lambda_i)} \cos \left(\frac{\lambda_i c m t}{a} \right) \right]$$

Analytic Conclusions

- Hankel and SOV produce the same expression

$$u(r, t) = \frac{P_o}{T_m} \left[\frac{(a^2 - r^2)}{4} - 2a^2 \sum_{i=1,2}^{\infty} \frac{J_o\left(\frac{\lambda_i r}{a}\right)}{\lambda_i^3 J_1(\lambda_i)} \cos\left(\frac{\lambda_i c m t}{a}\right) \right]$$

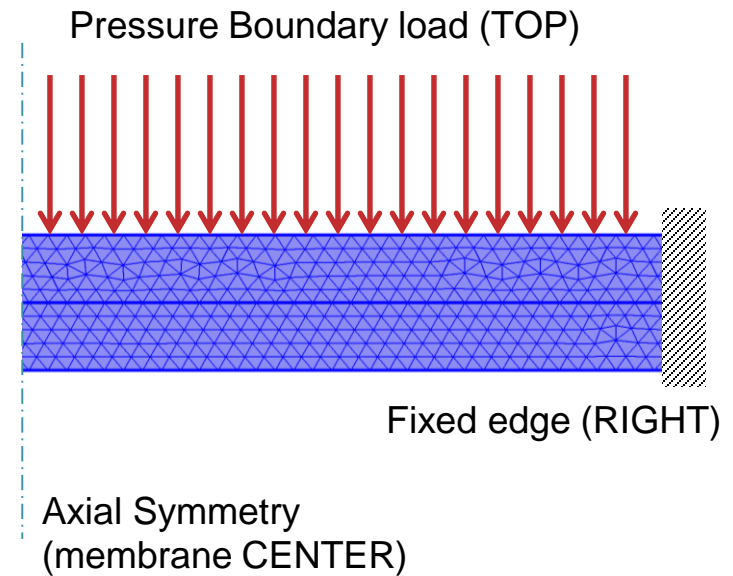
$$u(r, t, \theta) = T(t)\Theta(\theta)J_{\alpha,k}(z_{\alpha,k}r/r_o)$$

$$\omega = f(T_m(P_o))$$

Finite Element Analysis - Approach

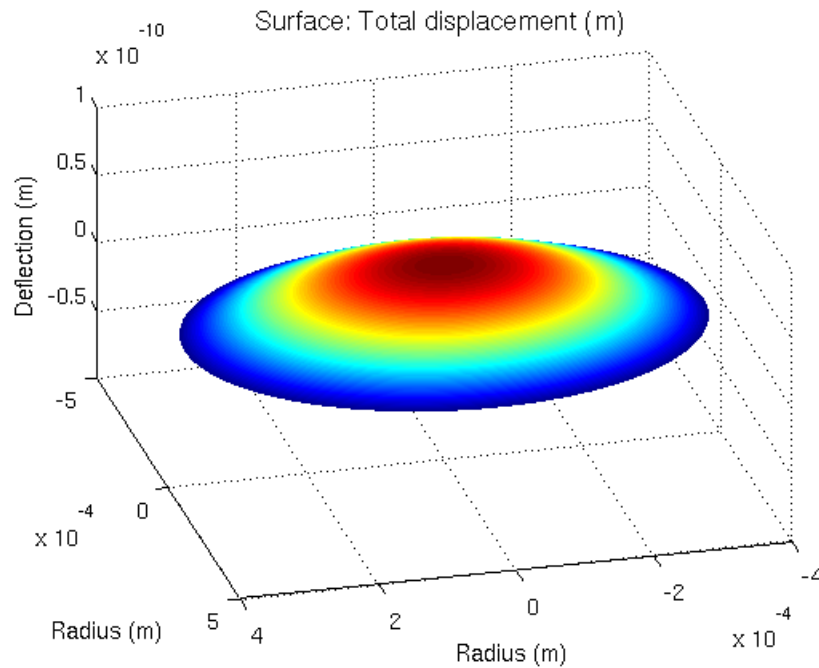
COMSOL Multiphysics was used to implement numerical solution

- **Model**
 - Axisymmetric 2D model
 - Nonlinear, Large deformations
- **Boundary Conditions**
 - Clamped edge
 - Symmetry
- **Load**
 - Pressure
- **Analysis**
 - Static
 - Prestressed Eigenfrequency

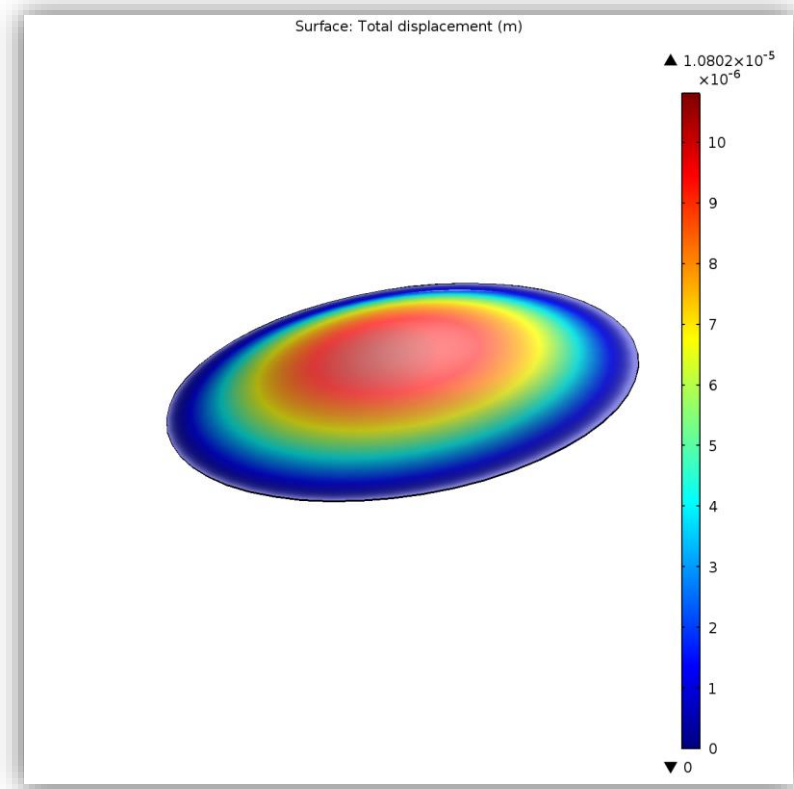


Material Property	Aluminum Nitride
Density (kg/m ³)	3260
Young's Modulus (Pa)	340 × 10 ⁹
Poisson's Ratio	0.3

Results: Mode Shape

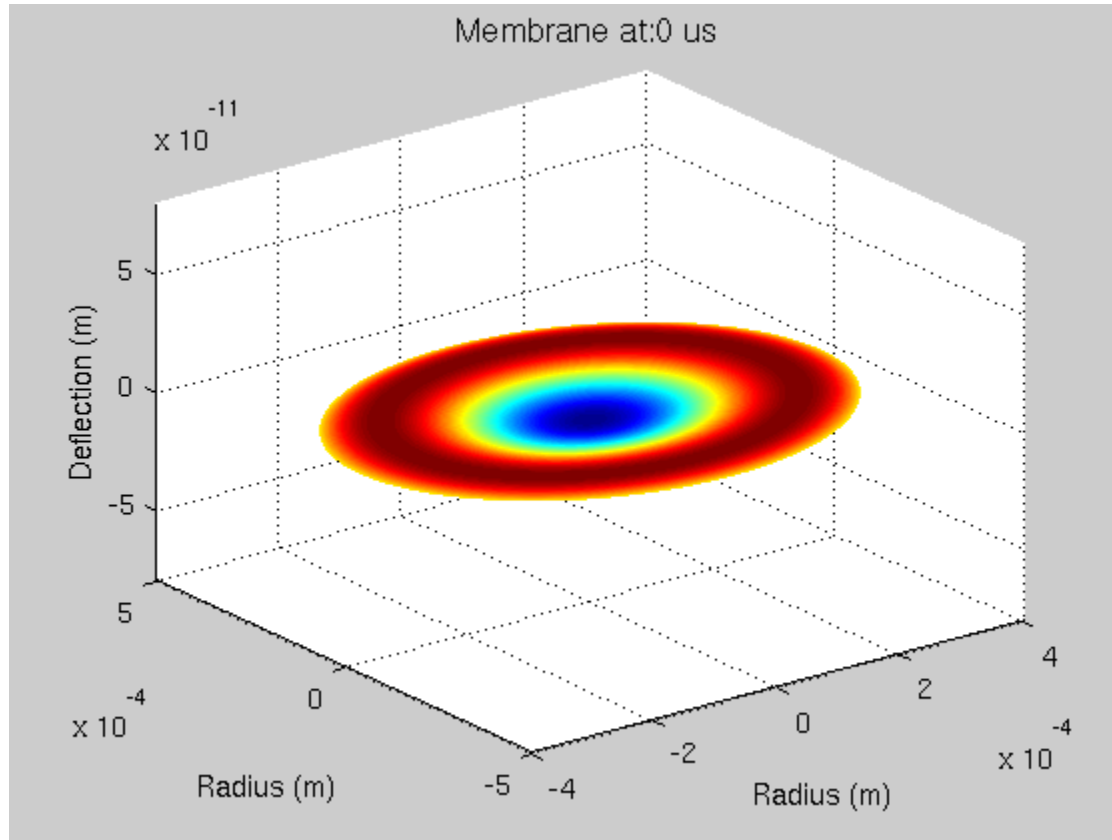


Analytical Result



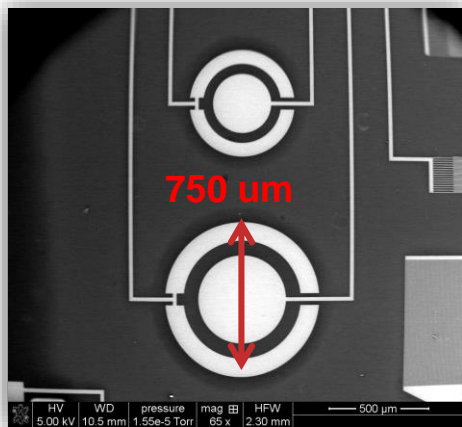
FEA Result

Results: Video

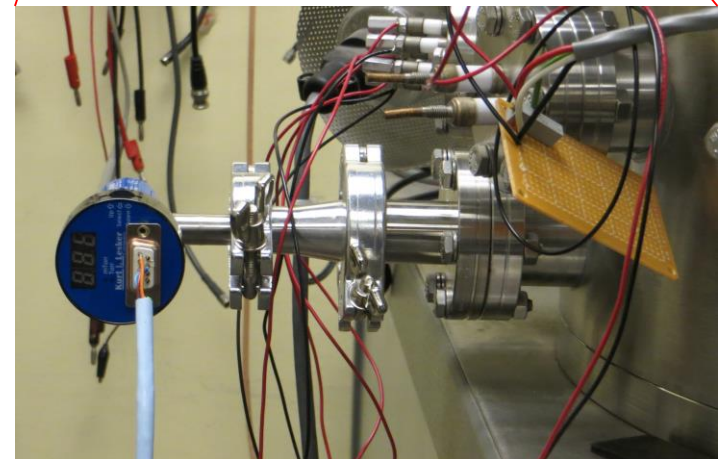
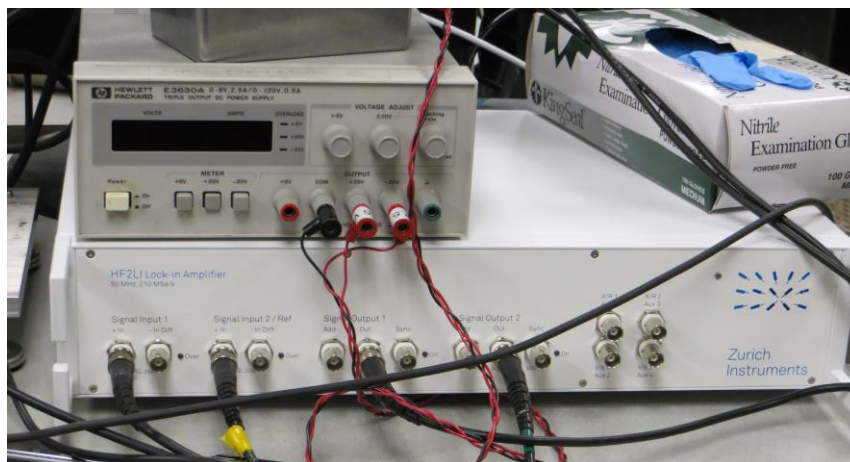
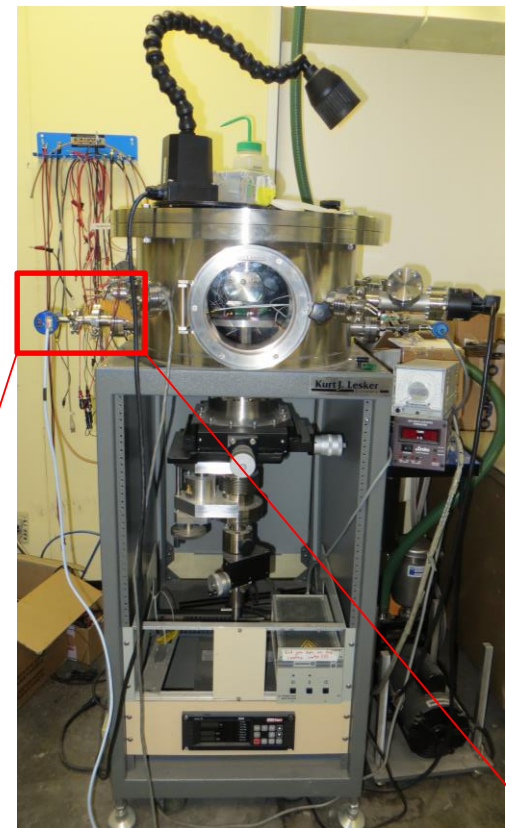


Analytical Result

Experimental Setup & MEMs Chip

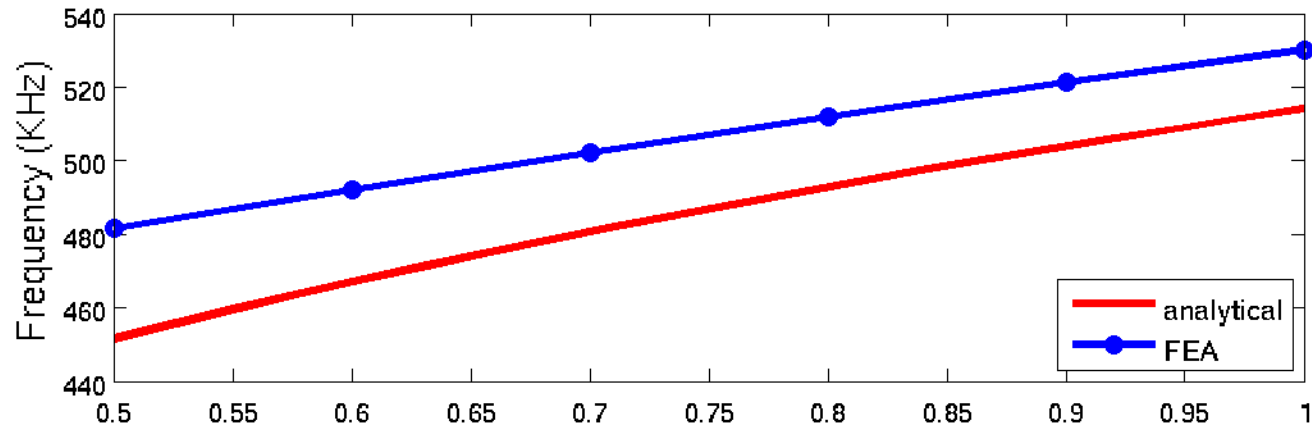


Actual MEMs Pressure Sensor on a chip

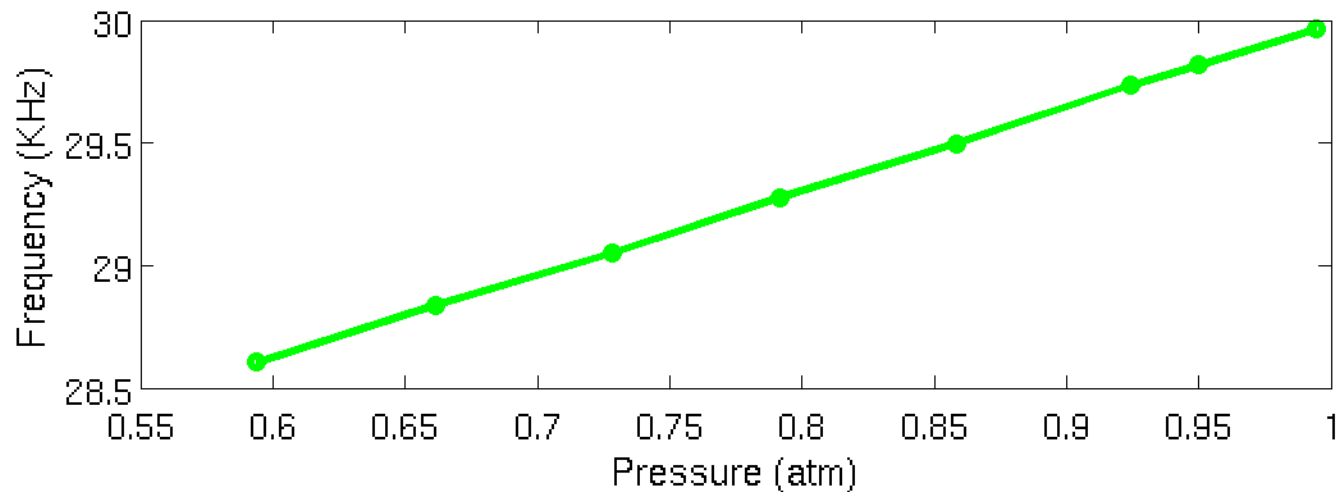


Results: Frequency vs. Pressure

Membrane Frequency vs. Pressure: Numerical & FEA

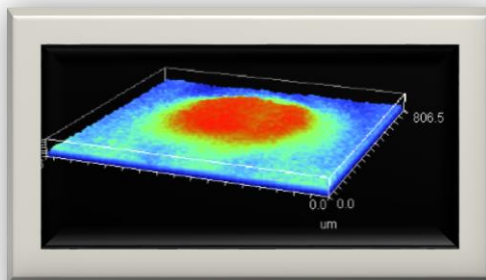


Membrane Frequency vs. Pressure: Experimental

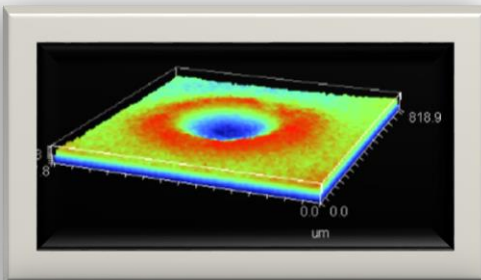


Sources of error → Future Work

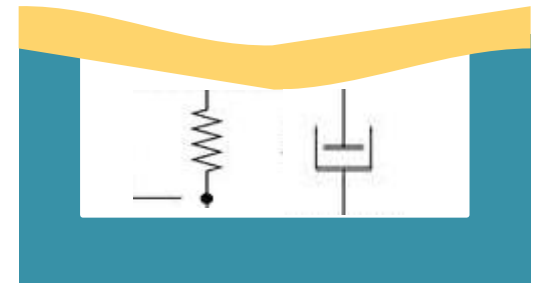
- Damping effects – squeeze film damping
- Substrate interaction
- Initial stress estimation of released film



600 um membrane defelction, NO PRESSURE



600 um membrane defelction, PRESSURE ON



Spring-Damper model for Squeeze film damping

Acknowledgements

- Fabian Goericke, GSR who helped take experimental measurements

Key References

- Selvadurai A., “Partial Differential Equations in Mechanics”
- Reynolds, “Introduction to PDEs Class Notes”



**Thank You.
Any Questions?**